

**Notice of References Cited**

Application/Control No.

10/578,769

Applicant(s)/Patent Under  
Reexamination  
TAKEI ET AL.

Examiner

DIEU HIEN T. DUONG

Art Unit

2821

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,600,449	07-2003	Onaka et al.	343/700MS
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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